



Workshop:
**Scanning Probe Microscopies :
Recent Techniques and Future Developments
for Biology and Materials Science**

April 26th, 2010
Auditorium SUD19 – Croix du Sud (Parking P11-P12) -Louvain-la-Neuve

Organized by the Belgian Society for Microscopy (BSM)

- 9:00 – 9:30 Registration – Poster installation
9:30 – 10:20 **Ricardo Garcia** (Instituto de Microelectronica de Madrid, Madrid, SPAIN)
Bimodal Atomic Force Microscopy: Fundamentals and Applications
10:20 – 11:00 Coffee Break – Poster Session – Exhibition
11:00 – 11:25 **B. Volbert** (Namitec): *In-Situ Atomic Force Microscopy: SEM Meets AFM*
11:25 – 11:50 **R. Zoetemelk** (ST Instruments): *Nanopipette Applications In Bionanoscience*
11:50 – 12:15 **L. Weisser** (Asylum Research): *Application of Piezo Force Microscopy to Biological Samples*
12:15 – 13:30 Lunch – Poster Session – Exhibition
13:30 – 14:20 **Simon Scheuring** (Institut Curie, Paris, FRANCE)
High Resolution AFM of Native Membranes: Structures and Dynamics
14:20 – 14:45 **U. Schmidt** (WITec): *The Confocal Raman AFM: A Nondestructive, High-Resolution Materials Characterisation Tool*
14:45 – 15:10 **S. Lemeshko** (NT-MDT): *AFM-SNOM-Raman and Tip Enhanced Raman Studies of Modern Nanostructures*
15:10 – 15:40 Coffee Break – Poster Session – Exhibition
15:40 – 16:05 **E. Paris** (Veeco): *Peak Force Tapping: A New AFM Mode for Imaging and Mechanical Properties Mapping*
16:05 – 16:55 **Thierry Melin** (ISEN/IEMN, Lille, FRANCE)
Electrostatic and Kelvin Probe Microscopy of Nanostructures and Nanodevices
16:55 – 17:00 General Conclusions

Registration: **mandatory before April 10th on www.nano.be**
BSM members: free of charge – Others: 5.- euros

Informations:

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